

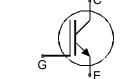
IGBT Chip in NPT-technology

FEATURES:

- 1200V NPT technology 180µm chip
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling
- integrated gate resistor

This chip is used for:

power module BSM50GD120DLC



Applications:

drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC81T120R2CL	1200\/	50A	9.08 X 8.98 mm ²	sawn on foil	Q67041-
SIGCOTT IZUNZUL	12000	307	9.00 / 0.90 11111	Sawii oli ioli	A4700-A001

MECHANICAL PARAMETER:

Raster size	9.08 X 8.98			
Emitter pad size	8 x (2.6 x 1.78)			
Gate pad size	1.46 x 0.8			
Area total / active	81.5 / 63.5			
Thickness	180	μm		
Wafer size	150	mm		
Flat position	90	grd		
Max.possible chips per wafer	167 pcs			
Passivation frontside	Photoimide			
Emitter metallization	3200 nm Al Si 1%			
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	electrically conductive glue or solder			
Wire bond Al, <500μm				
Reject Ink Dot Size	Ø 0.65mm ; max 1.2mm			
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C			



MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage, <i>T</i> _j =25 °C	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	1)	Α
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	150	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

¹⁾ depending on thermal properties of assembly

STATIC CHARACTERISTICS (tested on chip), T_{j} =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
Tarameter		Conditions	min.	typ.	max.]
Collector-emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V , I _C =3mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =50A	1.8	2.2	2.6	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	I _C =2mA , V _{GE} =V _{CE}	4.5	5.5	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			6.2	μA
Gate-emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			300	nA
Integrated gate resistor	R _{Gint}			5		Ω

ELECTRICAL CHARACTERISTICS (tested at component):

Parameter	Symbol	Conditions	Value			Unit
rarameter			min.	typ.	max.	Ollit
Input capacitance	Ciss	V _{CE} =25V,	-	3.3	-	nF
Output capacitance	Coss	$V_{GE}=0V$,	-	-	-	
Reverse transfer capacitance	C _{rss}	f=1MHz	-	0.21	-	

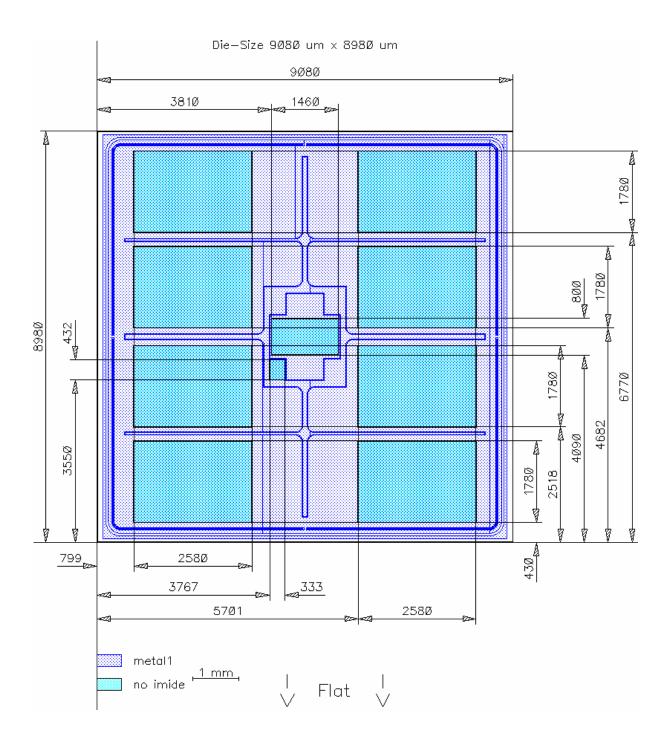
SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions 1)	Value			Unit
			min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	T _j =125°C	-	60	-	ns
Rise time	t _r	$V_{\rm CC} = 600 \text{V},$ $I_{\rm C} = 50 \text{A},$	-	50	-	
Turn-off delay time	$t_{d(off)}$	$V_{\text{GE}} = \pm 15 \text{V},$	-	300	-	
Fall time	t_{f}	$R_{\rm G}$ = 15 Ω	-	70	-	

¹⁾ values also influenced by parasitic L- and C- in measurement and package.



CHIP DRAWING:





FURTHER ELECTRICAL CHARACTERISTICS:

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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